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Selection Guide

	Description	-10	-12	-15	Unit
Maximum Access Time		10	12	15	ns
Maximum Operating Current	Commercial	90	85	-	mA
	Industrial/Automotive-A	100	95	-	mA
	Automotive-E	-	-	95	mA
Maximum CMOS Standby Current	Commercial/Industrial/ Automotive-A	10	10	-	mA
	Automotive-E	-	-	15	mA

Pin Configuration

Figure 1. 36-Pin SOJ (Top View)

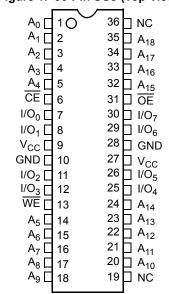
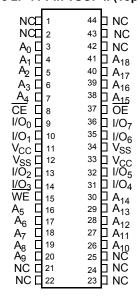


Figure 2. 44-Pin TSOP II (Top View)



Pin Definitions

Pin Name	36 SOJ Pin Number	44 TSOP II Pin Number	I/O Type	Description
A ₀ -A ₁₈	1–5,14–18, 20–24,32–35	3–7,16–20, 26–30,38–41	Input	Address inputs used to select one of the address locations.
I/O ₀ –I/O ₇	7,8,11,12,25, 26,29,30	9,10,13,14, 31,32,35,36	Input/Output	Bidirectional data I/O lines. Used as input or output lines depending on operation
NC ^[1]	19,36	1,2,21,22,23,2 4,25,42,43, 44	No Connect	No connects. This pin is not connected to the die
WE	13	15	Input/Control	Write Enable input, active LOW. When selected LOW, a WRITE is conducted. When selected HIGH, a READ is conducted.
CE	6	8	Input/Control	Chip Enable input, active LOW. When LOW, selects the chip. When HIGH, deselects the chip.
ŌĒ	31	37	Input/Control	Output Enable, active LOW. Controls the direction of the I/O pins. When LOW, the I/O pins are allowed to behave as outputs. When deasserted HIGH, I/O pins are three-stated, and act as input data pins.
V _{SS} , GND	10,28	12,34	Ground	Ground for the device. Should be connected to ground of the system.
V _{CC}	9,27	11,33	Power Supply	Power supply inputs to the device.

Note

[+] Feedback

^{1.} NC pins are not connected on the die.



Maximum Ratings

Exceeding maximum ratings may impair the useful life of the device. These user guidelines are not tested.

Ambient Temperature with

Supply Voltage on V_{CC} to Relative GND^[2] $\!-\!0.5$ V to +4.6 VDC

Voltage Applied to Outputs

Input Voltage^[2] $-0.5 \text{ V to V}_{CC} + 0.5 \text{ V}$

Operating Range

Range	Ambient Temperature	V _{CC}
Commercial	0°C to +70°C	$3.3~V\pm0.3~V$
Industrial/ Automotive-A	–40°C to +85°C	
Automotive-E	-40°C to +125°C	

Electrical Characteristics

Over the Operating Range

Parameter	Description	Tost Condition	Test Conditions		10		12	_	15	Unit
Farameter	Description	Test Condition	ıs	Min	Max	Min	Max	Min	Max	Oiiit
V _{OH}	Output HIGH Voltage	V_{CC} = Min.; I_{OH} = -4.0 mA		2.4		2.4		2.4		V
V_{OL}	Output LOW Voltage	V _{CC} = Min.,; I _{OL} = 8.0 mA			0.4		0.4		0.4	V
V _{IH}	Input HIGH Voltage			2.0	V _{CC} + 0.3	2.0	V _{CC} + 0.3	2.0	V _{CC} + 0.3	V
V_{IL}	Input LOW Voltage[2]			-0.3	0.8	-0.3	0.8	-0.3	0.8	V
I _{IX}	Input Load Current	$GND \leq V_I \leq V_CC$	Com'l/Ind'l/ Auto-A	-1	+1	-1	+1			μА
			Auto-E					-20	+20	
I _{CC}	V _{CC} Operating	V _{CC} = Max.,	Com'l		90		85			mA
	Supply Current	$f = f_{MAX} = 1/t_{RC}$	Ind'I/Auto-A		100		95			
			Auto-E						95	
I _{SB1}	Automatic CE Power Down Current	Max. V_{CC} , $\overline{CE} \ge V_{IH}$; $V_{IN} \ge V_{IH}$ or	Com'l/Ind'l/ Auto-A		40		40			mA
	—TTL Inputs V_{IN} ≤ V_{IN}	$V_{IN} \leq V_{IL}$, $f = f_{MAX}$	Auto-E						45	mΑ
I _{SB2}	Automatic CE Power Down Current	$\frac{\text{Max. V}_{\text{CC}},}{\text{CE}} \ge \text{V}_{\text{CC}} - 0.3 \text{ V},$	Com'l/Ind'l/ Auto-A		10		10			mA
	—CMOS Inputs	$V_{IN} \ge V_{CC} - 0.3 \text{ V},$ or $V_{IN} \le 0.3 \text{ V}, f = 0$	Auto-E						15	mA

Capacitance

Tested initially and after any design or process changes that may affect these parameters.

Parameter	Description	Test Conditions	Max	Unit
C _{IN}	Input Capacitance	$T_A = 25^{\circ}C$, $f = 1$ MHz,	8	pF
C _{OUT}	I/O Capacitance	V _{CC} = 3.3 V	8	pF

Thermal Resistance

Tested initially and after any design or process changes that may affect these parameters.

Parameter	Description	Test Conditions	36-Pin SOJ	44-TSOP-II	Unit
Θ_{JA}	to Ambient)	Test conditions follow standard test methods and procedures for	46.51	41.66	°C/W
Θ_{JC}		measuring thermal impedance, per EIA / JESD51.	18.8	10.56	°C/W

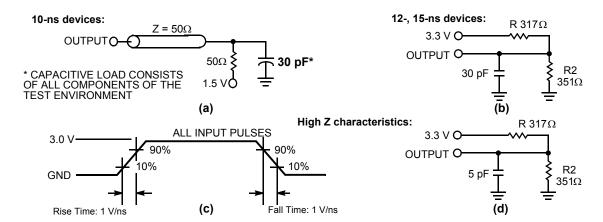
Notes

- V_{IL} (min) = -2.0 V and V_{IH} (max) = V_{CC} + 0.5 V for pulse durations of less than 20 ns.
 Tested initially and after any design or process changes that may affect these parameters.

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Figure 3. AC Test Loads and Waveforms [4]



Notes

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Tested initially and after any design or process changes that may affect these parameters.
 AC characteristics (except High Z) for 10 ns parts are tested using the load conditions shown in Figure (a). All other speeds are tested using the Thevenin load shown in Figure (b). High Z characteristics are tested for all speeds using the test load shown in Figure (d).



AC Switching Characteristics

Over the Operating Range [6]

		-1	0	-	-12	-		
Parameter	Description	Min	Max	Min	Max	Min	Max	Unit
Read Cycle		<u>'</u>	•		•			
t _{power} ^[7]	V _{CC} (typical) to the first access	100		100		100		μS
t _{RC}	Read Cycle Time	10		12		15		ns
t _{AA}	Address to Data Valid		10		12		15	ns
t _{OHA}	Data Hold from Address Change	3		3			3	ns
t _{ACE}	CE LOW to Data Valid		10		12		15	ns
t _{DOE}	OE LOW to Data Valid		5		6		7	ns
t _{LZOE}	OE LOW to Low Z	0		0		0		ns
t _{HZOE}	OE HIGH to High Z ^[8, 9]		5		6		7	ns
t _{LZCE}	CE LOW to Low Z ^[9]	3		3		3		ns
t _{HZCE}	CE HIGH to High Z ^[8, 9]		5		6		7	ns
t _{PU}	CE LOW to Power Up	0		0		0		ns
t _{PD}	CE HIGH to Power Down		10		12		15	ns
Write Cycle [10, 11]		•					
t _{WC}	Write Cycle Time	10		12		15		ns
t _{SCE}	CE LOW to Write End	7		8		10		ns
t _{AW}	Address Setup to Write End	7		8		10		ns
t _{HA}	Address Hold from Write End	0		0		0		ns
t _{SA}	Address Setup to Write Start	0		0		0		ns
t _{PWE}	WE Pulse Width	7		8		10		ns
t _{SD}	Data Setup to Write End	5		6		7		ns
t _{HD}	Data Hold from Write End	0		0		0		ns
t _{LZWE}	WE HIGH to Low Z ^[9]	3		3		3		ns
t _{HZWE}	WE LOW to High Z ^[8, 9]		5		6		7	ns

- Test conditions assume signal transition time of 3 ns or less, timing reference levels of 1.5 V, input pulse levels of 0 to 3.0 V.
 thower gives the minimum amount of time that the power supply should be at stable, typical V_{CC} values until the first memory access can be performed.
 thacet, thacet, thacet, and thack are specified with a load capacitance of 5 pF as in part (d) of AC Test Loads. Transition is measured ±500 mV from steady-state voltage.
 At any temperature and voltage condition, thacet is less than that the transition of either of the memory is defined by the overlap of CE LOW, and WE LOW. CE and WE must be LOW to initiate a Write, and the transition of either of these signals can terminate the Write. The input data setup and hold timing should be referenced to the leading edge of the signal that terminates the Write.
 The minimum Write cycle time for Write Cycle No. 3 (WE controlled, OE LOW) is the sum of that the transition of the terminates the Write.



Switching Waveforms

Figure 4. Read Cycle No. 1 (Address Transition Controlled) [12, 13]

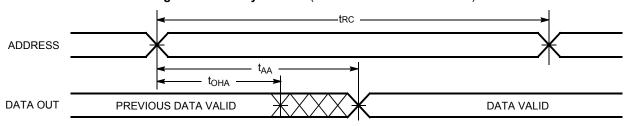


Figure 5. Read Cycle No. 2 (OE Controlled) [13, 14]

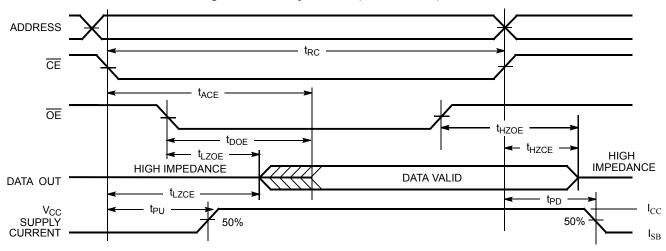
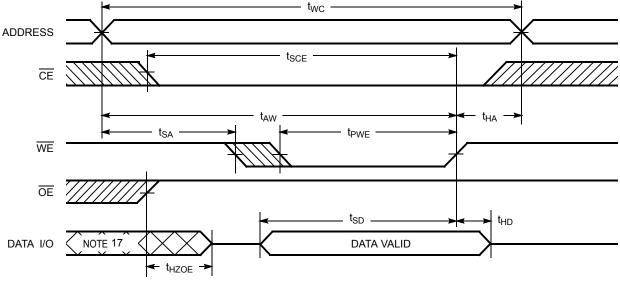


Figure 6. Write Cycle No. 1 (WE Controlled, OE HIGH During Write) [15, 16]



Notes

- 12. <u>Device</u> is continuously selected. <u>OE</u>, <u>CE</u> = V_{IL}.

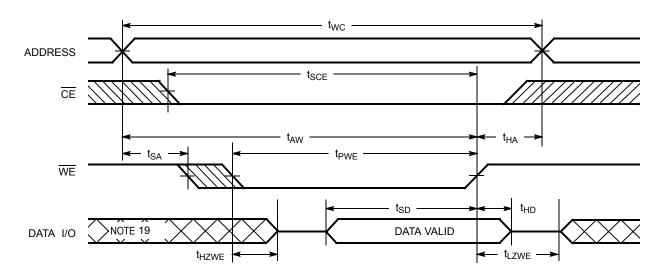
 13. <u>WE</u> is HIGH for read cycles.
- 14. Address valid before or similar to $\overline{\text{CE}}$ transition LOW.
- 15. Data I/O is high impedance if \overline{OE} = $V_{|H:}$.
 16. If \overline{CE} goes HIGH simultaneously with \overline{WE} HIGH, the output remains in high impedance state.
- 17. During this period, the I/Os are in output state. Do not apply input signals.

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Switching Waveforms (continued)

Figure 7. Write Cycle No. 2 ($\overline{\text{WE}}$ Controlled, $\overline{\text{OE}}$ LOW) [18]



Truth Table

CE	OE	WE	I/O ₀ –I/O ₇	Mode	Power
Н	Х	Χ	High Z	Power Down	Standby (I _{SB})
L	L	Н	Data Out	Read	Active (I _{CC})
L	Х	L	Data In	Write	Active (I _{CC})
L	Н	Н	High Z	Selected, Outputs Disabled	Active (I _{CC})

[+] Feedback

Notes

18. If $\overline{\text{CE}}$ goes HIGH simultaneously with $\overline{\text{WE}}$ HIGH, the output remains in high impedance state.

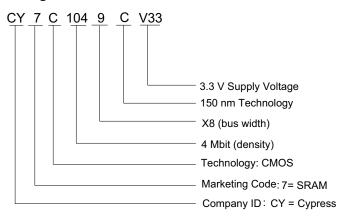
19. During this period, the I/Os are in output state. Do not apply input signals.



Ordering Information

Speed (ns)	Ordering Code	Package Diagram	Package Type	Operating Range
10	CY7C1049CV33-10VXC	51-85090	36-Pin (400-Mil) Molded SOJ (Pb-free)	Commercial
	CY7C1049CV33-10VXA	51-85090	36-Pin (400-Mil) Molded SOJ (Pb-free)	Automotive-A
	CY7C1049CV33-10ZXC	51-85087	44-Pin TSOP II (Pb-free)	Commercial
12	CY7C1049CV33-12ZSXA	51-85087	44-Pin TSOP II (Pb-free)	Automotive-A
15	CY7C1049CV33-15VXE	51-85090	36-Pin (400-Mil) Molded SOJ (Pb-free)	Automotive-E
	CY7C1049CV33-15ZSXE	51-85087	44-Pin TSOP II (Pb-free)	Automotive-E

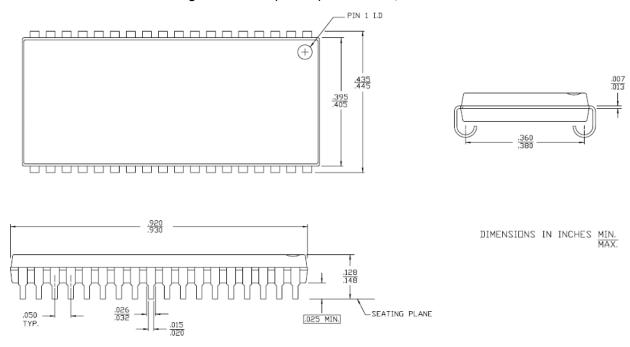
Ordering Code Definitions





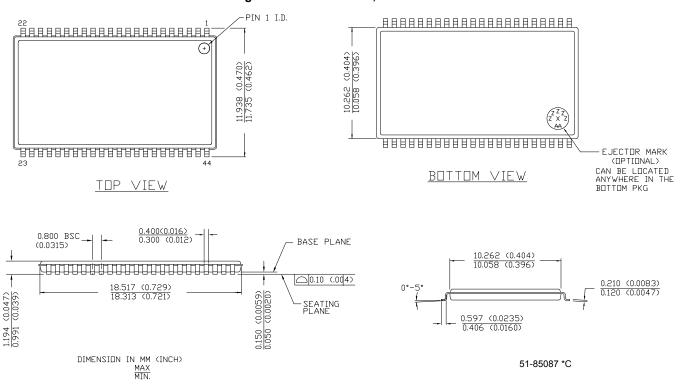
Package Diagrams

Figure 8. 36-Pin (400-Mil) Molded SOJ, 51-85090



51-85090 *D

Figure 9. 44-Pin TSOP II, 51-85087



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Acronyms

Table 1. Acronyms Used in this Document

Acronym	Description			
TR	Thermal Resistance			
CE	Chip Enable			
ŌĒ	Output Enable			
RD	Row Decoder			
IB	Input Buffer			
RAM	Random Access Memory			
I/O	Input/Output			
MAT	Maximum Access Time			
MOC	Maximum Operating Current			

[+] Feedback



Document History Page

Document Title: CY7C1049CV33 4-Mbit (512K X 8) Static RAM Document Number: 38-05006				
Rev.	ECN	Orig. of Change	Submission Date	Description of Change
**	112569	HGK	03/06/02	New data sheet
*A	114091	DFP	04/25/02	Changed Tpower unit from ns to μs
*B	116479	CEA	09/16/02	Add applications foot note to data sheet, page 1.
*C	262949	RKF	See ECN	Added Automotive-E Specs Added $\Theta_{\rm JA}$ and $\Theta_{\rm JC}$ values on Page #3.
*D	300091	RKF	See ECN	Added -20-ns Speed bin
*E	344595	SYT	See ECN	Added Pb-free package on page #8 Removed shading for CY7C1049CV33-15ZSXE in the ordering Information on page 9
*F	2615344	VKN/PYRS	12/03/08	Added Automotive-A information Removed 8 ns and 20 ns speed bins, Changed t_{POWER} spec from 1 μs to 100 μs , Updated Ordering Information table.
*G	2841563	NXR/	01/07/2010	Added CY7C1049CV33-10VXA to Ordering Info table.
*H	2898958	AJU	03/25/10	Removed inactive parts from the ordering information table. Updated package diagrams.
*	2954734	AJU	06/30/2010	New Part Number added CY7C1049CV33-10ZXC to Ordering Info table.

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